

K Vedam

List of Publications by Year in Descending Order

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The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

157
papers

3,907
citations

37
h-index

54
g-index

163
ext. papers

4,108
ext. citations

2.6
avg, IF

4.57
L-index

#	Paper	IF	Citations
157	Spectroscopic ellipsometry: a historical overview. <i>Thin Solid Films</i> , 1998 , 313-314, 1-9	2.2	114
156	Ion-implantation induced anomalous surface amorphization in silicon. <i>Nuclear Instruments & Methods in Physics Research B</i> , 1994 , 85, 335-339	1.2	32
155	Characterization of inhomogeneous transparent thin films on transparent substrates by spectroscopic ellipsometry: refractive indices $n(\lambda)$ of some fluoride coating materials. <i>Applied Optics</i> , 1994 , 33, 2664-71	1.7	22
154	Optical Characterization of Inhomogeneous Transparent Films on Transparent Substrates by Spectroscopic Ellipsometry. <i>Physics of Thin Films</i> , 1994 , 191-247		15
153	Characterization of Ferroelectric Films by Spectroscopic Ellipsometry. <i>Physics of Thin Films</i> , 1994 , 249-278		1
152	Effect of preparation conditions on the morphology and electrochromic properties of amorphous tungsten oxide films. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 1993 , 11, 1881-1887	2.9	39
151	Ion-implantation-caused special damage profiles determined by spectroscopic ellipsometry in crystalline and in relaxed (annealed) amorphous silicon. <i>Thin Solid Films</i> , 1993 , 233, 117-121	2.2	9
150	Hydrogen diffusion and reaction processes in thin films investigated by real time spectroscopic ellipsometry. <i>Thin Solid Films</i> , 1993 , 233, 276-280	2.2	8
149	Spectroscopic ellipsometry studies on ion beam sputter deposited Pb(Zr, Ti)O ₃ films on sapphire and Pt-coated silicon substrates. <i>Thin Solid Films</i> , 1993 , 230, 15-27	2.2	41
148	Studies on inhomogeneous transparent optical coatings on transparent substrates by spectroscopic ellipsometry. <i>Thin Solid Films</i> , 1993 , 234, 439-442	2.2	16
147	Determination of the optical function $n(\lambda)$ of vitreous silica by spectroscopic ellipsometry with an achromatic compensator. <i>Applied Optics</i> , 1993 , 32, 6391-8	1.7	24
146	Monitoring ion etching of GaAs/AlGaAs heterostructures by real time spectroscopic ellipsometry: Determination of layer thicknesses, compositions, and surface temperature. <i>Applied Physics Letters</i> , 1992 , 60, 2776-2778	3.4	16
145	Real time spectroscopic ellipsometry characterization of the nucleation of diamond by filament-assisted chemical vapor deposition. <i>Journal of Applied Physics</i> , 1992 , 71, 5287-5289	2.5	26
144	Determination of the optical constants of an inhomogeneous transparent LaF ₃ thin film on a transparent substrate by spectroscopic ellipsometry. <i>Optics Letters</i> , 1992 , 17, 538-40	3	26
143	Comparative study of the effect of annealing of nitrogen-implanted silicon-on-insulator structures by spectroscopic ellipsometry, cross-sectional transmission electron microscopy and Rutherford backscattering spectroscopy. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , 1992 , 12, 177-184	3.1	8
142	Morphology Control Of The Electrochromic Effect In Tungsten Oxide Thin Films. <i>Materials Research Society Symposia Proceedings</i> , 1991 , 255, 275		4
141	Real time monitoring of filament-assisted chemically vapor deposited diamond by spectroscopic ellipsometry. <i>Surface and Coatings Technology</i> , 1991 , 49, 381-386	4.4	9

140	Ion beam etching of GaAs and GaAs/AlGaAs heterostructures probed in real time by spectroscopic ellipsometry. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 1991 , 9, 810-815	2.9	14
139	Characterization of ion beam-induced surface modification of diamond films by real time spectroscopic ellipsometry. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 1991 , 9, 1123-1128	2.9	21
138	Real Time Spectroscopic Ellipsometry: In Situ Characterization of Pyrrole Electropolymerization. <i>Journal of the Electrochemical Society</i> , 1991 , 138, 3266-3275	3.9	55
137	Temperature dependence of optical constants of MoS(2) for pyrooptical devices. <i>Applied Optics</i> , 1991 , 30, 1583-4	1.7	3
136	Optical characterization of a four-medium thin film structure by real time spectroscopic ellipsometry: amorphous carbon on tantalum. <i>Applied Optics</i> , 1991 , 30, 2692-703	1.7	39
135	Real time monitoring of filament-assisted chemically vapor deposited diamond by spectroscopic ellipsometry 1991 , 381-386		
134	Real-time spectroscopic ellipsometry study of the electrochemical deposition of polypyrrole thin films. <i>Thin Solid Films</i> , 1990 , 193-194, 350-360	2.2	12
133	Real-time spectroscopic ellipsometry for determination of the optical functions of ion-beam-deposited hydrogenated amorphous carbon. <i>Thin Solid Films</i> , 1990 , 193-194, 361-370	2.2	5
132	Spectroscopic ellipsometry studies of crystalline silicon implanted with carbon ions. <i>Journal of Applied Physics</i> , 1990 , 67, 3555-3559	2.5	27
131	Characterization of the interface between Ge ⁺ -implanted crystalline silicon and its thermally grown oxide by spectroscopic ellipsometry. <i>Journal of Applied Physics</i> , 1990 , 67, 599-603	2.5	17
130	Fast scanning spectroelectrochemical ellipsometry: In-situ characterization of gold oxide. <i>Surface Science</i> , 1990 , 233, 341-350	1.8	66
129	Thin-film deposition by a new laser ablation and plasma hybrid technique. <i>Applied Physics Letters</i> , 1989 , 54, 2455-2457	3.4	111
128	Real-time and spectroscopic ellipsometry characterization of diamond and diamond-like carbon. <i>Thin Solid Films</i> , 1989 , 181, 565-578	2.2	30
127	Simultaneous determination of refractive index, its dispersion and depth-profile of magnesium oxide thin film by spectroscopic ellipsometry. <i>Applied Optics</i> , 1989 , 28, 2691-4	1.7	27
126	Simultaneous determination of dispersion relation and depth profile of thorium fluoride thin film by spectroscopic ellipsometry. <i>Thin Solid Films</i> , 1988 , 166, 325-334	2.2	37
125	High-dose carbon ion implantation studies in silicon. <i>Thin Solid Films</i> , 1988 , 163, 323-329	2.2	13
124	Spectroscopic ellipsometry of amorphous Ni _{0.95} Tb _{0.05} and crystalline nickel. <i>Materials Science and Engineering</i> , 1988 , 99, 281-283		4
123	Investigation of the void structure in amorphous germanium thin films as a function of low-energy ion bombardment. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 1988 , 6, 1631-1635	2.9	86

122	Spectroscopic ellipsometry of sputtered amorphous Ni _{0.95} Tb. <i>Physical Review B</i> , 1988 , 38, 1562-1565	3.3	3
121	SIMULTANEOUS DETERMINATION OF DISPERSION RELATION AND DEPTH PROFILE OF THORIUM FLUORIDE THIN FILM BY SPECTROSCOPIC ELLIPSOMETRY 1988 , 325-334		
120	Processing & Characterization Of Thin Films Of SiO ₂ On Si For Integrated Circuits 1988 , 0945, 84		1
119	Intrinsic Stress in a-Germanium Films Deposited by RF-Magnetron Sputtering. <i>Materials Research Society Symposia Proceedings</i> , 1988 , 130, 355		8
118	Nondestructive Depth-Profiling of Multilayer Structures by Spectroscopic Ellipsometry. <i>MRS Bulletin</i> , 1987 , 12, 21-23	3.2	10
117	Formation and nondestructive characterization of ion implanted silicon-on-insulator layers. <i>Applied Physics Letters</i> , 1987 , 51, 343-345	3.4	34
116	Thickness dependence of optical gap and void fraction for sputtered amorphous germanium. <i>Physical Review B</i> , 1987 , 35, 9368-9371	3.3	38
115	Nonuniformity in void concentration between the initial and final growth stage of sputtered a-Ge films studied using spectroscopic ellipsometry. <i>Physical Review B</i> , 1987 , 36, 6206-6208	3.3	7
114	Electrical, Optical and Structural Properties of Thin SiO ₂ Films On Si. <i>Materials Research Society Symposia Proceedings</i> , 1987 , 105, 169		4
113	High Dose Carbon Ion Implantation Studies in Silicon. <i>Materials Research Society Symposia Proceedings</i> , 1987 , 107, 483		1
112	Formation And Nondestructive Characterization Of Ion Implanted Soi Layers 1987 , 0797, 77		
111	Nondestructive depth profiling of ZnS and MgO films by spectroscopic ellipsometry. <i>Optics Letters</i> , 1987 , 12, 456-8	3	23
110	Thickness-dependent void fraction of rf-sputtered amorphous Ge films by spectroscopic ellipsometry. <i>Applied Physics Letters</i> , 1986 , 49, 328-330	3.4	25
109	Analytic solution of the pseudo-Brewster angle. <i>Journal of the Optical Society of America A: Optics and Image Science, and Vision</i> , 1986 , 3, 1772	1.8	37
108	Proper choice of the error function in modeling spectroellipsometric data. <i>Applied Optics</i> , 1986 , 25, 2013-17	1.7	35
107	Density of amorphous germanium films by spectroscopic ellipsometry. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 1986 , 4, 577-582	2.9	33
106	Spectroscopic ellipsometry study of glow-discharge-deposited thin films of a-Ge:H. <i>Journal of Applied Physics</i> , 1986 , 60, 3724-3731	2.5	19
105	Spectroscopic ellipsometry: A new tool for nondestructive depth profiling and characterization of interfaces. <i>Journal of Applied Physics</i> , 1986 , 59, 694-701	2.5	104

104	Surface Roughness Characterization of Al Films by Spectroscopic Ellipsometry. <i>Materials Research Society Symposia Proceedings</i> , 1985 , 54, 669		1
103	Supersensitive Dial-Gage Measurement by Observing Rotation of Laser Speckles. <i>Experimental Techniques</i> , 1985 , 9, 16-17	1.4	1
102	Ar ion beam and CCl ₄ reactive ion etching: A comparison of etching damage and of damage passivation by hydrogen. <i>Journal of Applied Physics</i> , 1985 , 58, 4282-4291	2.5	19
101	Nondestructive depth profiling by spectroscopic ellipsometry. <i>Applied Physics Letters</i> , 1985 , 47, 339-341	3.4	116
100	Roughness measurements by spectroscopic ellipsometry. <i>Applied Optics</i> , 1985 , 24, 3773	1.7	37
99	Pressure dependence of the refractive index and dielectric constant in a fluoroperovskite, KMgF ₃ . <i>Physical Review B</i> , 1984 , 29, 6921-6925	3.3	20
98	Electrical characteristics of r.f.-sputtered CdTe thin-films for photovoltaic applications. <i>Solid-State Electronics</i> , 1984 , 27, 329-337	1.7	18
97	Spectroscopic Ellipsometry Study of rf-Sputtered a-Ge Films. <i>Materials Research Society Symposia Proceedings</i> , 1984 , 38, 301		7
96	Refractive index of liquids at high pressures. <i>Critical Reviews in Solid State and Materials Sciences</i> , 1983 , 11, 1-45	10.1	19
95	Complete 3-D deformation analysis in the white light speckle method. <i>Applied Optics</i> , 1983 , 22, 213-4	1.7	4
94	Processing speckle photography data: circular imaging aperture. <i>Applied Optics</i> , 1983 , 22, 653-4	1.7	15
93	Selective counting path of Young's fringes in speckle photography for eliminating diffraction halo effects. <i>Applied Optics</i> , 1983 , 22, 2242-3	1.7	12
92	Characterization of Ion Implanted Silicon by Spectroscopic Ellipsometry and Cross Section Transmission Electron Microscopy. <i>Materials Research Society Symposia Proceedings</i> , 1983 , 27, 299		3
91	The Study of Damage Profile of Ion Implanted Layer on Si by Spectroscopic Ellipsometry. <i>Materials Research Society Symposia Proceedings</i> , 1982 , 14, 529		3
90	Importance of using Eulerian representation of strain in high pressure studies on liquids. <i>Journal of Chemical Physics</i> , 1982 , 77, 1461-1463	3.9	16
89	Direct observation of laser speckles for real-time analysis of lateral motions. <i>Optics Letters</i> , 1981 , 6, 511-3		5
88	Stress-optic coefficient of ZnSe at 10.6 microm. <i>Applied Optics</i> , 1981 , 20, 2878-9	1.7	4
87	Speckle photography of lateral sinusoidal vibrations: error due to varying halo intensity. <i>Applied Optics</i> , 1981 , 20, 3388-91	1.7	16

86	Explosive crystallization of rf-sputtered amorphous CdTe films. <i>Journal of Electronic Materials</i> , 1981 , 10, 433-443	1.9	22
85	Piezo- and thermo-optic behavior of LiTaO ₃ . <i>Journal of Applied Physics</i> , 1981 , 52, 944-947	2.5	9
84	Characterization of surfaces of laser-annealed samples by ellipsometry. <i>Surface Science</i> , 1980 , 96, 319-3288		3
83	Laser speckle photography for supersensitive dial gauge. <i>Optics Letters</i> , 1980 , 5, 441-2	3	3
82	Piezo- and elasto-optic properties of liquids under high pressure. III. Results on twelve more liquids. <i>Journal of Chemical Physics</i> , 1980 , 73, 4577-4584	3.9	23
81	Piezo- and elasto-optic properties of deuterium oxide under high pressure. <i>Journal of Chemical Physics</i> , 1980 , 72, 1410-1411	3.9	1
80	Application of fringe shifting technique in speckle photography 1979 , 12, 341-346		2
79	A critical evaluation of equations of state by piezo-optic measurements. <i>Journal of Applied Physics</i> , 1979 , 50, 1328-1333	2.5	7
78	Testing the trueness of circular surfaces: a simple holographic method. <i>Applied Optics</i> , 1979 , 18, 627-30	1.7	1
77	Testing the trueness of circular surfaces by laser speckle photography. <i>Applied Optics</i> , 1979 , 18, 2351-3	1.7	1
76	Measurement of subspeckle-size changes by laser-speckle photography. <i>Optics Letters</i> , 1979 , 4, 406	3	8
75	Piezo-Optic Behavior and the Equation of State of Liquids 1979 , 421-427		
74	Piezo- and elasto-optic properties of liquids under high pressure. II. Refractive index vs density. <i>Journal of Chemical Physics</i> , 1978 , 69, 4772-4778	3.9	63
73	Piezo- and elasto-optic properties of liquids under high pressure. I. Refractive index vs pressure and strain. <i>Journal of Chemical Physics</i> , 1978 , 69, 4762-4771	3.9	63
72	Unusual white light conoscopic figure in single crystal lithium metagermanate Li(2)GeO(3). <i>Applied Optics</i> , 1978 , 17, 3339_1	1.7	2
71	Retroreflection from spherical glass beads in highway pavement markings. 1: Specular reflection. <i>Applied Optics</i> , 1978 , 17, 1855-8	1.7	17
70	Retroreflection from spherical glass beads in highway pavement markings. 2: Diffuse reflection (a first approximation calculation). <i>Applied Optics</i> , 1978 , 17, 1859-69	1.7	16
69	The Pressure Dependence of the Magnetic Susceptibility of Rare-Earth Substituted Samarium Sulfide 1978 , 187-204		

68	Optical interferometry in liquids at high pressures to 14 kilobars. <i>Review of Scientific Instruments</i> , 1977 , 48, 245-246	1.7	19
67	Ellipsometric studies of environment-sensitive polish layers of glass. <i>Journal of Applied Physics</i> , 1977 , 48, 1155-1157	2.5	12
66	Variation of refractive index of polystyrene with pressure to 7 kbar. <i>Journal of Applied Physics</i> , 1976 , 47, 2443-2446	2.5	4
65	Generalized ellipsometric method for the determination of all the optical constants of the system: Optically absorbing film on an absorbing substrate. <i>Surface Science</i> , 1976 , 56, 49-63	1.8	24
64	Characterization of defects in real surfaces by ellipsometry. <i>Surface Science</i> , 1976 , 56, 221-236	1.8	22
63	Piezo- and thermo-optic behavior of spinel (MgAl ₂ O ₄). <i>Journal of Solid State Chemistry</i> , 1975 , 12, 213-218	3.3	16
62	Piezo-optic Behavior of Water and Carbon Tetrachloride under High Pressure. <i>Physical Review Letters</i> , 1975 , 35, 1014-1016	7.4	18
61	Dispersion of the Elasto-Optic Constants of Potassium Halides 1975 , 169-177		5
60	Characterization of real surfaces of vitreous silica by ellipsometry. <i>Materials Research Bulletin</i> , 1974 , 9, 1503-1509	5.1	20
59	Growth of color centres and hardening of CaF ₂ by heavy dose of irradiation. <i>Physica Status Solidi A</i> , 1973 , 19, 625-634		3
58	OPTICAL STUDIES ON THE HIGH PRESSURE PHASE TRANSFORMATIONS IN SILVER IODIDE SINGLE CRYSTALS 1973 , 91-99		2
57	Nonlinear variation of the induced birefringence of vitreous silica with uniaxial stress to 7 kbar. <i>Journal of Applied Physics</i> , 1972 , 43, 3724-3728	2.5	5
56	Variation of the refractive index of boric oxide glasses with hydrostatic pressure to 7 kbar. <i>Journal of Applied Physics</i> , 1972 , 43, 3623-3627	2.5	11
55	Hardening of CaF ₂ single-crystal surfaces due to contamination by atmospheric oxygen. <i>Journal of Applied Physics</i> , 1972 , 43, 4396-4400	2.5	4
54	Direct Optical Observation of the Semiconductor-to-Metal Transition in SmS under Pressure. <i>Physical Review B</i> , 1972 , 6, 3023-3026	3.3	74
53	Generalized Ellipsometric Method for the Absorbing Substrate Covered with a Transparent-Film System Optical Constants of Silicon at 3655 Å. <i>Journal of the Optical Society of America</i> , 1972 , 62, 16		42
52	Optical Constants of Silicon at 5461 Å. <i>Journal of the Optical Society of America</i> , 1972 , 62, 596		9
51	Characterization of real surfaces by ellipsometry. <i>Surface Science</i> , 1972 , 29, 379-395	1.8	51

50	Piezo-optic behavior of forsterite, Mg ₂ SiO ₄ . <i>Journal of Physics and Chemistry of Solids</i> , 1972 , 33, 1251-1255	3.5	13
49	Characterisation of thin surface films on germanium in various solvents by ellipsometry. <i>Journal of Materials Science</i> , 1971 , 6, 969-973	4.3	7
48	Electroreflectance in GeSi alloys under hydrostatic pressure. <i>Solid State Communications</i> , 1971 , 9, 1187-1191	4.1	38
47	Optical Anisotropy of Silicon Single Crystals. <i>Physical Review B</i> , 1971 , 3, 2567-2571	3.3	83
46	Epitaxial Growth of Ice Crystals on the Muscovite Cleavage Plane and Their Relation to Partial Dislocations. <i>Journal of Applied Physics</i> , 1971 , 42, 516-520	2.5	19
45	The study of dislocations in muscovite mica by X-ray transmission topography. <i>Philosophical Magazine and Journal</i> , 1970 , 22, 255-268		8
44	Finite size effects on lattice vibrations of ionic crystals and measurements of infrared absorption spectra. <i>Physica Status Solidi A</i> , 1970 , 3, 647-656		13
43	Examination of Imperfect Muscovite Crystals by X-Ray Diffraction Methods. <i>Journal of Applied Physics</i> , 1970 , 41, 50-53	2.5	12
42	Piezo-Optic Properties of Amorphous Selenium at a Wavelength of 115 μ . <i>Journal of the Optical Society of America</i> , 1970 , 60, 800		15
41	Pressure Dependence of the Refractive Indices of the Hexagonal Crystals Beryl, CdS, ZnS, and ZnO. <i>Physical Review</i> , 1969 , 181, 1196-1201		49
40	THIN FILM CHARACTERIZATION BY ELECTRON MICROPROBE AND ELLIPSOMETRY: SiO ₂ FILMS ON SILICON. <i>Applied Physics Letters</i> , 1969 , 14, 43-45	3.4	7
39	Variation of the refractive indices of KBr and KI with pressure to 14 kbars. <i>Materials Research Bulletin</i> , 1969 , 4, 573-579	5.1	30
38	Optical constants of germanium by ellipsometry. <i>Physics Letters, Section A: General, Atomic and Solid State Physics</i> , 1969 , 29, 428-429	2.3	5
37	Ellipsometric Method for the Determination of All the Optical Parameters of the System of an Isotropic Nonabsorbing Film on an Isotropic Absorbing Substrate Optical Constants of Silicon*. <i>Journal of the Optical Society of America</i> , 1969 , 59, 64		50
36	Simultaneous and Independent Determination of the Refractive Index and the Thickness of Thin Films by Ellipsometry*. <i>Journal of the Optical Society of America</i> , 1968 , 58, 526		27
35	Pressure Dependence of the Refractive Indices of the Tetragonal Crystals: ADP, KDP, CaMoO ₄ , CaWO ₄ , and Rutile*. <i>Journal of the Optical Society of America</i> , 1968 , 58, 1446		44
34	PIEZO- AND THERMO-OPTIC BEHAVIOR OF LiNbO ₃ . <i>Applied Physics Letters</i> , 1968 , 12, 138-140	3.4	11
33	Variation of the refractive indices of calcite, with pressure to 7 kbar. <i>Physica Status Solidi (B): Basic Research</i> , 1968 , 26, 285-290	1.3	7

32	Photoelastic Properties of Sapphire (Al_2O_3). <i>Journal of Applied Physics</i> , 1967 , 38, 4555-4556	2.5	24
31	Nonlinear Variation of the Refractive Indices of Quartz with Pressure*. <i>Journal of the Optical Society of America</i> , 1967 , 57, 1140		40
30	Non-linear piezo-optics. <i>Acta Crystallographica</i> , 1967 , 22, 630-634		17
29	Elastic Constants of Selenium in the Hexagonal and Glassy Phases. <i>Journal of Applied Physics</i> , 1966 , 37, 3432-3434	2.5	50
28	Variation of Refractive Index of MgO with Pressure to 7 kbar. <i>Physical Review</i> , 1966 , 146, 548-554		82
27	Piezo-optic behaviour of rubidium chloride up to the phase transition point. <i>Journal of Materials Science</i> , 1966 , 1, 310-312	4.3	13
26	Variation of the refractive indices of CaF_2 , BaF_2 and PbF_2 with pressure to 7 kb. <i>Journal of Physics and Chemistry of Solids</i> , 1966 , 27, 1563-1566	3.9	62
25	Nonlinear Variation of Refractive Index of Vitreous Silica with Pressure to 7 Kbars. <i>Journal of the American Ceramic Society</i> , 1966 , 49, 531-535	3.8	46
24	The Laser as a Light Source for Ultramicroscopy and Light Scattering by Imperfections in Crystals. Investigation of Imperfections in LiF, MgO, and Ruby. <i>Journal of Applied Physics</i> , 1966 , 37, 2551-2557	2.5	30
23	Nonlinear Piezo-Optic Behavior of Sphalerite (ZnS). <i>Physical Review</i> , 1966 , 150, 766-767		15
22	Raman spectrum of strontium titanate. <i>European Physical Journal A</i> , 1961 , 163, 158-164	2.5	47
21	Crystal Structure of Ferroelectric $\text{LiH}_3(\text{SeO}_3)_2$. <i>Physical Review</i> , 1960 , 119, 1252-1255		38
20	Ferroelectric Transition in Rubidium Bisulfate. <i>Physical Review</i> , 1960 , 117, 1502-1503		81
19	$\text{LiH}_3(\text{SeO}_3)_2$: New Room-Temperature Ferroelectric. <i>Physical Review</i> , 1959 , 114, 1217-1218		83
18	Non-isomorphism of ferroelectric phases of ammonium sulfate and ammonium fluoberyllate. <i>Acta Crystallographica</i> , 1958 , 11, 307-307		37
17	Ammonium Hydrogen Sulfate: A New Ferroelectric with Low Coercive Field. <i>Physical Review</i> , 1958 , 111, 1508-1510		112
16	Room-Temperature Ferroelectricity in Lithium Hydrazinium Sulfate, $\text{Li}(\text{N}_2\text{H}_5)\text{SO}_4$. <i>Physical Review</i> , 1958 , 111, 1467-1468		77
15	Dielectric and Thermal Study of $(\text{NH}_4)_2\text{SO}_4$ and $(\text{NH}_4)_2\text{BeF}_4$ Transitions. <i>Physical Review</i> , 1958 , 112, 405-412		181

14	Ferroelectricity in Di-Glycine Nitrate $(\text{NH}_2\text{CH}_2\text{COOH})_2\text{HNO}_3$. <i>Physical Review</i> , 1958 , 111, 430-432	82
13	New Room-Temperature Ferroelectric. <i>Physical Review</i> , 1958 , 110, 1309-1311	45
12	Photoelastic properties of barite. <i>Proceedings of the Indian Academy of Sciences - Section A</i> , 1951 , 34, 161	7
11	Photoelastic constants of sodium chlorate from ultrasonic diffraction. <i>Proceedings of the Indian Academy of Sciences - Section A</i> , 1951 , 34, 240	6
10	Elastic and photoelastic properties of some optical glasses. <i>Proceedings of the Indian Academy of Sciences - Section A</i> , 1950 , 31, 450-458	13
9	The Elastic and Photoelastic Constants of Fused Quartz. <i>Physical Review</i> , 1950 , 78, 472-473	22
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